

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BASU ET AL.	
		Examiner Toan D. Nguyen	Art Unit 2665	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0051449	05-2002	Iwata, Atsushi	370/389
*	B	US-2003/0012145	01-2003	Bragg, Nigel	370/254
*	C	US-6,130,890	10-2000	Leinwand et al.	370/400
*	D	US-2002/0049762	04-2002	Shah et al.	707/10
*	E	US-6,981,055	12-2005	Ahuja et al.	709/238
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.